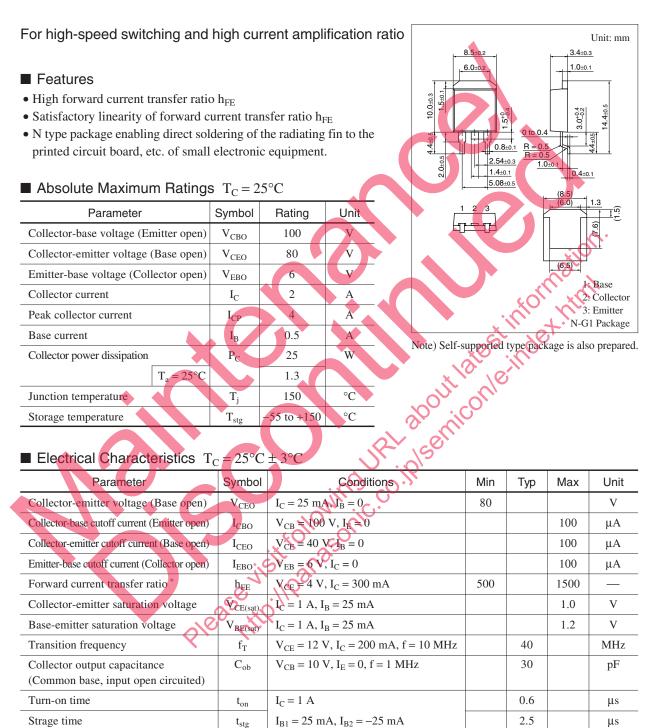
2SD1775A

Silicon NPN triple diffusion planar type



Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

 $V_{CC} = 50 \text{ V}$

 t_{f}

2. *: Rank classification

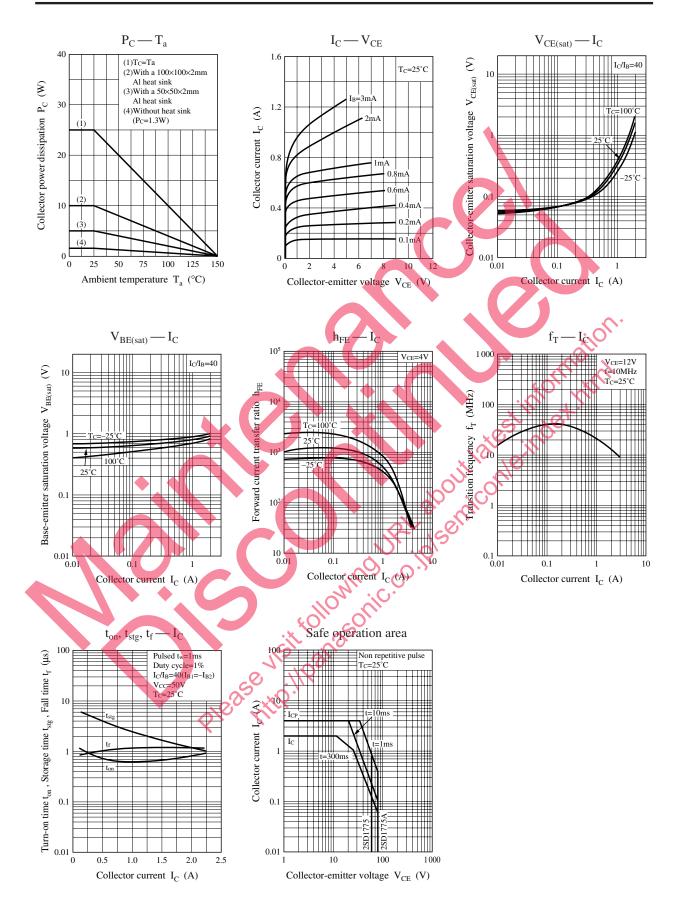
Rank	R	Q
h _{FE}	500 to 1000	800 to 1500

Publication date: April 2003

μs

1.0

Fall time



Panasonic



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